CALL FOR PAPERS
Real-World Image Annotation and Retrieval
IEEE Transactions on Pattern Analysis and Machine Intelligence
Special Issue
November Issue of 2008

IEEE Transaction on Pattern Analysis and Machine Intelligence seeks original manuscripts for a Special Issue on Real-World Image Annotation and Retrieval scheduled to appear in **the November issue of 2008.**

Indexing and retrieval of large quantities of imagery data is a highly challenging and increasingly important research problem for the pattern analysis and machine intelligence research community. Researchers in computer vision, machine learning, signal and image processing, mathematical statistics, and databases have worked on image annotation and retrieval for over a decade. A number of significant technological advances have been achieved in the field. Some of the techniques have been applied to real problems such as art image retrieval, biomedical information management, education, sensor networks, large-scale online personal and professional photo sharing, classification and filtering of images on the Web, finding scientific content (remote sensing and biodiversity), computer forensics, and threat assessment. We envision more image annotation and retrieval work of high impact to emerge in the coming years. In this special issue, we aim at showcasing the latest technological advances for solving real problems.

We are soliciting high-quality contributions in the following areas of interest:

• Web-scale machine-assisted annotation and retrieval of images
• Intelligent summarization and visualization for large-scale image retrieval
• Statistical and relevance feedback models for interactive search
• Annotation and retrieval for scientific discovery, biodiversity, and the arts
• Image retrieval in computer forensics, threat assessment, and other security areas

Submitted articles must not have been previously published or currently submitted for journal publication elsewhere. As an author, you are responsible for understanding and adhering to our submission guidelines. You can access them at http://www.computer.org/mc/tpami/author.htm. Please thoroughly read these before submitting your manuscript.

The papers should be submitted online at the IEEE Transactions on Pattern Analysis and Machine Intelligence submission site (https://mc.manuscriptcentral.com/tpami-cs) with a note/tag designating the manuscript to this special issue. All submissions will be peer-reviewed by at least 3 experts in the field. Priority will be given to work with high novelty and potential impacts. Please feel free to contact the Peer Review Supervisor, Suzanne Werner at swerner@computer.org or the guest editors at jwang@ist.psu.edu, geman@jhu.edu, rmgray@standford.edu, or jiebo.luo@kodak.com, if you have any questions. Please note the following important dates.

Important dates:
Updated **Submission Deadline: 23-September-2007**
Reviews Completed: 12-December-2007
Major Revisions Due: 12-February-2008
Reviews of Revisions Completed (if needed): 12-April-2008
Minor Revision Due (if needed): 24-April-2008
Notification of Final Acceptance: 06-May-2008
Publication Materials for Final Manuscripts Due: COB 16-May-2008
Publication Date: November 2008

GUEST EDITORS:

James Z. Wang The Pennsylvania State University	**Donald Geman** Johns Hopkins University
Robert M. Gray Stanford Universiy	**Jiebo Luo** Kodak Research Laboratories